

N-Channel 100 V (D-S) MOSFET

PRODUCT SUMMARY				
V_{DS}	100	V		
$R_{DS(on)} V_{GS} = 10 V$	32	mΩ		
I _D	9	Α		
Configuration	Single			

• Halogen-free According to IEC 61249-2-21 Definition

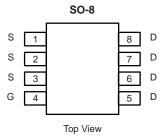
FEATURES

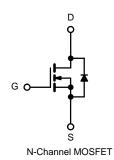
- Extremely Low Q_{gd} for Switching Losses
- 100 % R_g Tested
- 100 % Avalanche Tested
- Compliant to RoHS Directive 2002/95/EC



APPLICATIONS

· Primary Side Switch





Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V_{DS}	100	V	
Gate-Source Voltage		V_{GS}	± 20	v	
	T _C = 25 °C		9		
Continuous Drain Current (T = 150 °C)	T _C = 70 °C	1 , [6		
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	- ID	6 ^{b, c}		
	T _A = 70 °C	1 1	5 ^{b, c}	Α	
Pulsed Drain Current		I _{DM}	40		
Continuous Source-Drain Diode Current	T _C = 25 °C		7		
	T _A = 25 °C] ^I s	3.8 ^{b, c}		
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	30		
Single Pulse Avalanche Energy	L = 0.111111	E _{AS}	112	mJ	
Maximum Power Dissipation	T _C = 25 °C		14		
	T _C = 70 °C] , [5	W	
	T _A = 25 °C	- P _D	4 ^{b, c}	VV	
	T _A = 70 °C	1 1	2 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stq}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^{b, †}	t ≤ 10 s	R_{thJA}	33	40	°C/W		
Maximum Junction-to-Foot (Drain)	Steady State	$R_{th,IF}$	17	21]		

- a. Based on T_C = 25 °C.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. Maximum under steady state conditions is 80 °C/W.



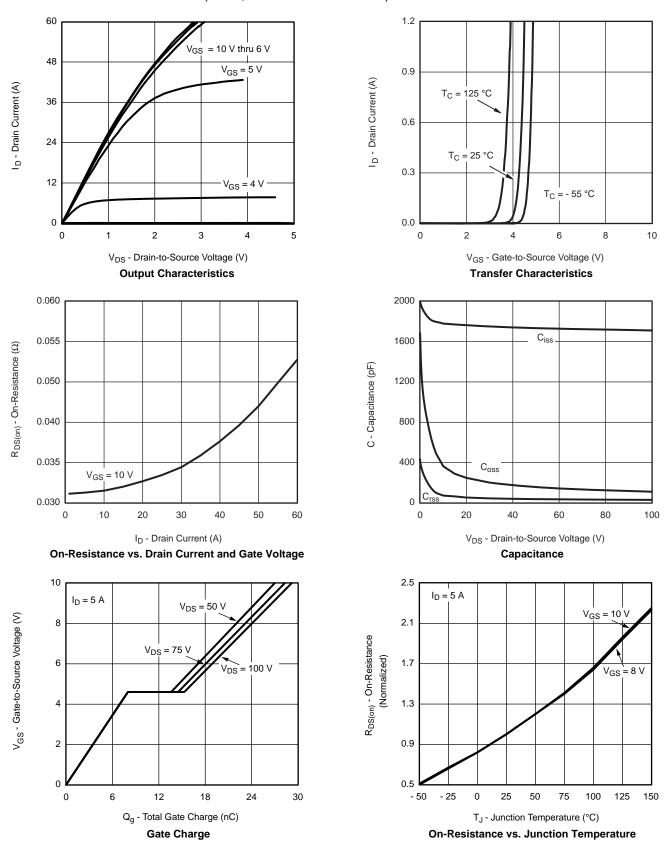
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	100			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	L = 250 uA		172		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 10		IIIV/ C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_{D} = 250 \mu\text{A}$	1.0		3.0	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zara Cata Valtaga Drain Current		V _{DS} = 100 V, V _{GS} = 0 V			1	
Zero Gate Voltage Drain Current	IDSS	V _{DS} = 100 V, V _{GS} = 0 V, T _J = 55 °C			10	μA
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 10 \text{ V}, V_{GS} = 10 \text{ V}$	30			Α
Drain Source On State Registered	В	V _{GS} = 10 V, I _D = 5 A		0.032		0
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 5 \text{ A}$		0.033		mΩ
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 5 A		20		S
Dynamic ^b						
Input Capacitance	C _{iss}			1900		pF
Output Capacitance	C _{oss}	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		150		
Reverse Transfer Capacitance	C _{rss}			50		
Total Gate Charge $Q_{g} = V_{DS} = 75 \text{ V, } V_{GS} = 10 \text{ V, } I_{DS}$		$V_{DS} = 75 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 5 \text{ A}$	28	28.5	43	
			23	35	nC	
Gate-Source Charge	Q_{gs}	$V_{DS} = 75 \text{ V}, V_{GS} = 8 \text{ V}, I_{D} = 5 \text{ A}$		8		
Gate-Drain Charge	Q_{gd}			6.5		
Gate Resistance	R_{g}	f = 1 MHz		0.80	1.3	Ω
Turn-on Delay Time	t _{d(on)}			14	21	
Rise Time	t _r	$V_{DD} = 50 \text{ V}, R_L = 10 \Omega$		12	18	_
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 5 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		22	33	
Fall Time	t _f			6	10	ne
Turn-On Delay Time	t _{d(on)}			16	24	ns
Rise Time	t _r	V_{DD} = 50 V, R_L = 10 Ω		12	18	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 5 \text{ A}, V_{GEN} = 8 \text{ V}, R_g = 1 \Omega$		20	30	
Fall Time	t _f			7	12	
Drain-Source Body Diode Characteristi	cs					
Continuous Source-Drain Diode Current	I _S	$T_C = 25 ^{\circ}C$			7.7	Α
Pulse Diode Forward Current ^a	I _{SM}				50	
Body Diode Voltage	V _{SD}	I _S = 2.6 A		0.77	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			63	95	ns
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 5 A, dI/dt = 100 A/μs, T _{.1} = 25 °C		110	165	nC
Reverse Recovery Fall Time	t _a	$_{iF}$ – 3 Λ , α_{i} α_{i} – 100 Λ / μ 5, ij = 23 Ω		49		ns
Reverse Recovery Rise Time	t _b			14		113

Notes:

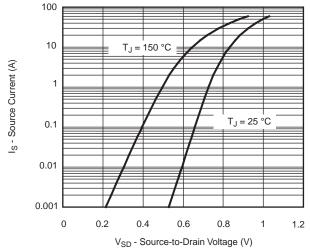
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%$
- a. Guaranteed by design, not subject to production testing.

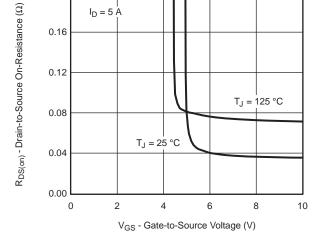
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.





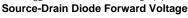


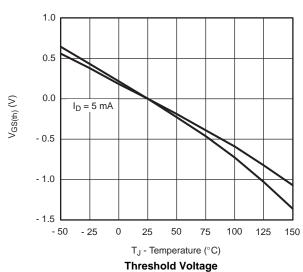


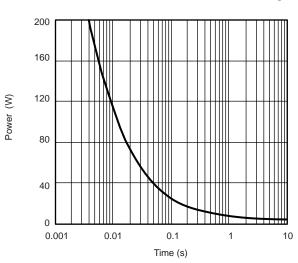


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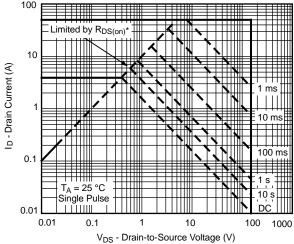
On-Resistance vs. Gate-to-Source Voltage







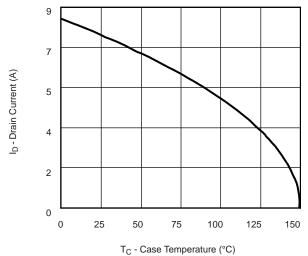
Single Pulse Power, Junction-to-Ambient



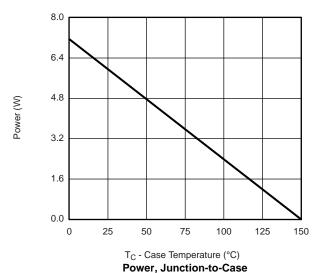
* V_{GS} > minimum V_{GS} at which R_{DS(on)} is specified

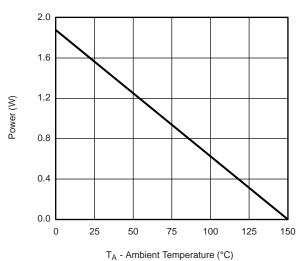
Safe Operating Area, Junction-to-Ambient







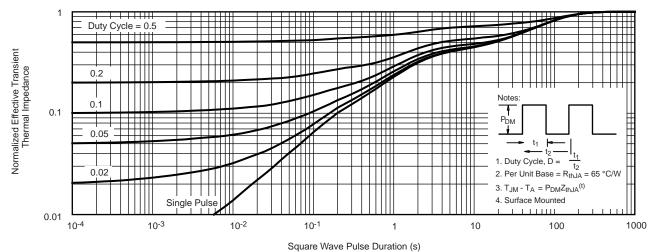




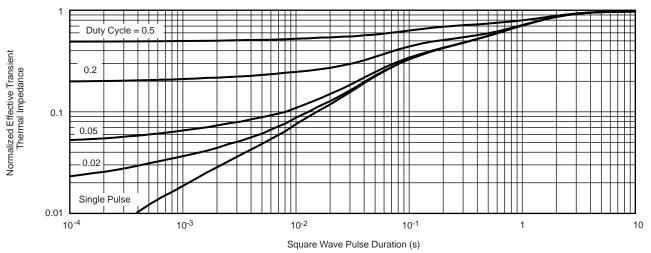
Power, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





Normalized Thermal Transient Impedance, Junction-to-Ambient



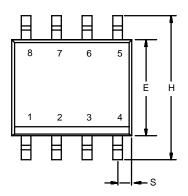
Normalized Thermal Transient Impedance, Junction-to-Foot

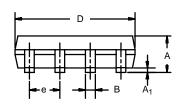
服务热线:400-655-8788

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SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012







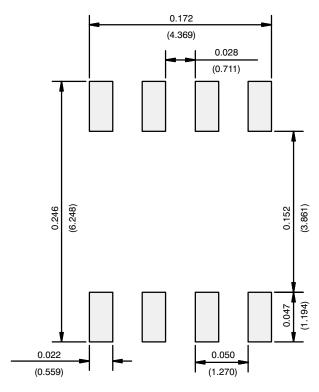
	MILLIMETERS			HES		
DIM	Min	Max	Min	Max		
Α	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27	BSC	0.050 BSC			
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
ECN: C-06527-Pay I 11-San-06						

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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